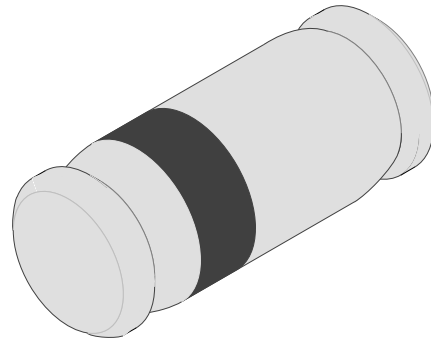# TEMIC

TELEFUNKEN Semiconductors

LL4148.LL4448

Silicon Epitaxial Planar Diodes

Features

- Electrical data identical with the devices 1N4148 and 1N4448 respectively

Applications

Extreme fast switches

94 9371

Absolute Maximum Ratings

$T_j = 25°C$

Parameter	Test Conditions	Type	Symbol	Value	Unit
Repetitive peak reverse voltage			V_{RRM}	100	V
Reverse voltage			V_R	75	V
Peak forward surge current	$t_p=1\mu s$		I_{FSM}	2	A
Repetitive peak forward current			I_{FRM}	450	mA
Forward current			I_F	200	mA
Average forward current	$V_R=0$		I_{FAV}	150	mA
Power dissipation			P_V	500	mW
Junction temperature			T_j	175	°C
Storage temperature range			T_{stg}	−65...+175	°C

Maximum Thermal Resistance

$T_j = 25°C$

Parameter	Test Conditions	Symbol	Value	Unit
Junction ambient	on PC board 50mmx50mmx16mm	R_{thJA}	500	K/W

Characteristics

$T_j = 25°C$

Parameter	Test Conditions	Type	Symbol	Min	Typ	Max	Unit
Forward voltage	I_F=5mA	LL4448	V_F	0.62		0.72	V
	I_F=50mA	LL4148	V_F		0.86	1	V
	I_F=100mA	LL4448	V_F		0.93	1	V
Reverse current	V_R=20 V		I_R			25	nA
	V_R=20 V, T_j=150 °C		I_R			50	μA
	V_R=75 V		I_R			5	μA
Breakdown voltage	I_R=100μA, t_p/T=0.01, t_p=0.3ms		$V_{(BR)}$	100			V
Diode capacitance	V_R=0, f=1MHz, V_{HF}=50mV		C_D			4	pF
Rectification efficiency	V_{HF}=2V, f=100MHz		η_r	45			%
Reverse recovery time	I_F=I_R=10mA, i_R=1mA		t_{rr}			8	ns
	I_F=10mA, V_R=6V, i_R=0.1xI_R, R_L=100Ω		t_{rr}			4	ns

Typical Characteristics ($T_j = 25°C$ unless otherwise specified)
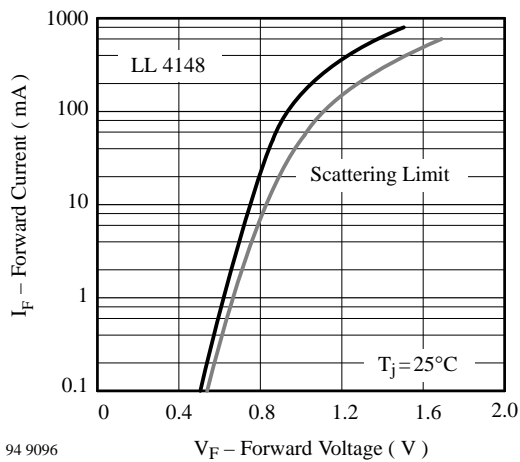

94 9096

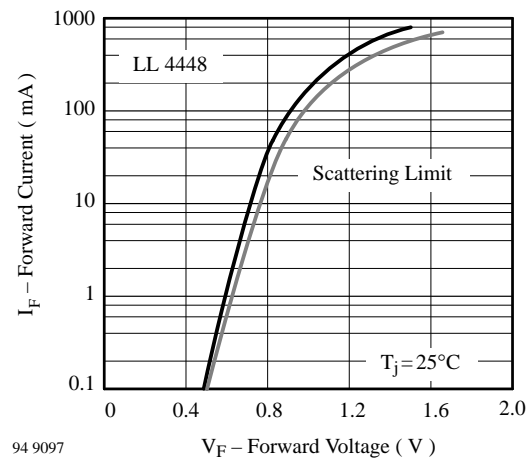**Figure 1 : Forward Current vs. Forward Voltage**

94 9097

Figure 2 : Forward Current vs. Forward Voltage
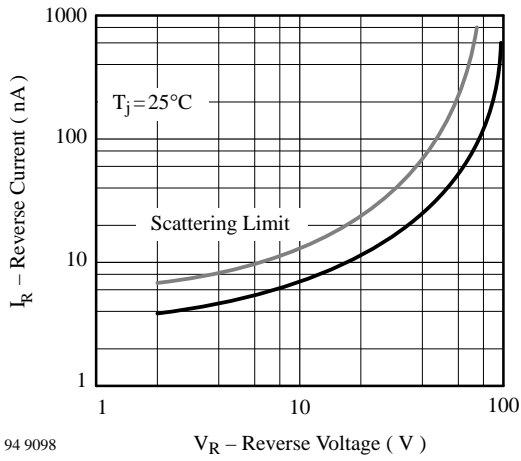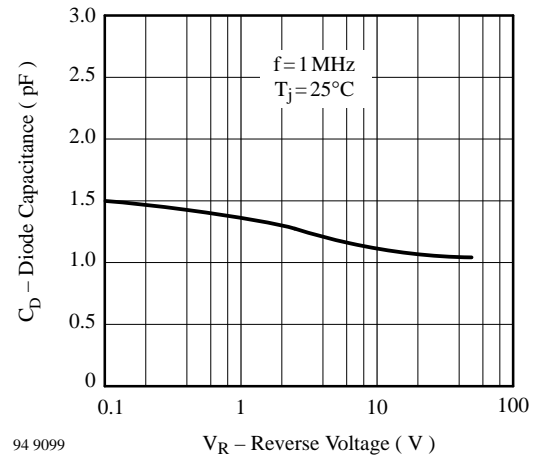
Figure 3 : Reverse Current vs. Reverse Voltage

Figure 4 : Diode Capacitance vs. Reverse Voltage

Dimensions in mm

Cathode Identification

technical drawings
according to DIN
specifications

94 9370

$\varnothing$ 1.5 max.

0.35
0.30

0.35
0.30

3.7
3.3

Glass Case
SOD 80 Mini MELF
Weight max 0.1 g
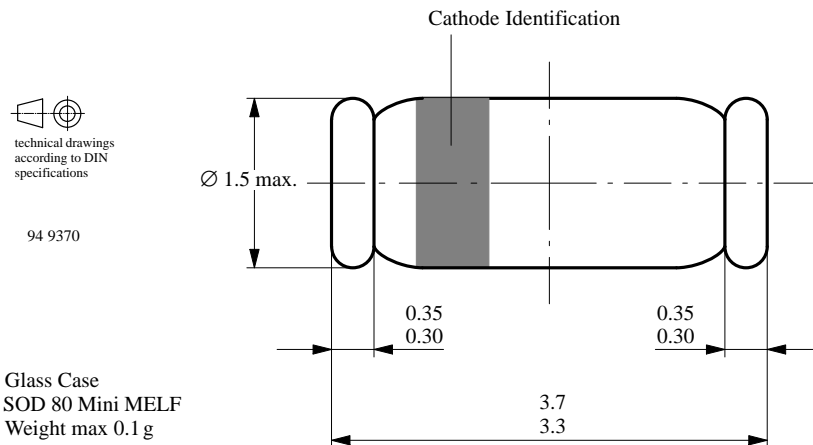
OZONE DEPLETING SUBSTANCES POLICY STATEMENT

It is the policy of **TEMIC TELEFUNKEN microelectronic GmbH** to

1. Meet all present and future national and international statutory requirements and

2. Regularly and continuously improve the performance of our products, processes, distribution and operating systems with respect to their impact on the health and safety of our employees and the public, as well as their impact on the environment.

Of particular concern is the control or elimination of releases into the atmosphere of those substances which are known as ozone depleting substances (ODSs).

The Montreal Protocol (1987) and its London Amendments (1990) will soon severely restrict the use of ODSs and forbid their use within the next ten years. Various national and international initiatives are pressing for an earlier ban on these substances.

TEMIC TELEFUNKEN microelectronic GmbH semiconductor division has been able to use its policy of continuous improvements to eliminate the use of any ODSs listed in the following documents.

1. Annex A, B and list of transitional substances of the Montreal Protocol and the London Amendments respectively

2. Class I and II ozone depleting substances in the Clean Air Act Amendments of 1990 by the Environmental Protection Agency (EPA) in the USA and

3. Council Decision 88/540/EEC and 91/690/EEC Annex A, B and C (transitional substances) respectively.

TEMIC can certify that our semiconductors are not manufactured with and do not contain ozone depleting substances.